

Search Notes

Application/Control No.

10/632,447

Examiner

Djenane M. Bayard

Applicant(s)/Patent under
Reexamination

BASU ET AL.

Art Unit

2141

SEARCHED

Class	Subclass	Date	Examiner
709	226	10/24/2007	DB
709	225	10/24/2007	DB
709	220	10/24/2007	DB
709	217	10/24/2007	DB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
709	226	10/24/2007	DB
709	225	10/24/2007	DB
709	217/220	10/24/2007	db

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	10/24/2007	DB
EIC Fast and Focus	10/22/2007	DB
Counsulted with W.Vaughn	10/18/2007	DB
Double Patent Search	10/22/2007	DB